Evy Eatlice Semiconductor Corporation - <u>LCMX02-1200ZE-1TG100C Datasheet</u>



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Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	160
Number of Logic Elements/Cells	1280
Total RAM Bits	65536
Number of I/O	79
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	100-LQFP
Supplier Device Package	100-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lcmxo2-1200ze-1tg100c

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MachXO2 Family Data Sheet Introduction

May 2016

Features

- Flexible Logic Architecture
 - Six devices with 256 to 6864 LUT4s and 18 to 334 I/Os
- Ultra Low Power Devices
 - Advanced 65 nm low power process
 - As low as 22 μW standby power
 - Programmable low swing differential I/Os
 - · Stand-by mode and other power saving options

Embedded and Distributed Memory

- Up to 240 kbits sysMEM™ Embedded Block RAM
- Up to 54 kbits Distributed RAM
- Dedicated FIFO control logic
- On-Chip User Flash Memory
 - Up to 256 kbits of User Flash Memory
 - 100,000 write cycles
 - Accessible through WISHBONE, SPI, I²C and JTAG interfaces
 - Can be used as soft processor PROM or as Flash memory

Pre-Engineered Source Synchronous I/O

- DDR registers in I/O cells
- Dedicated gearing logic
- 7:1 Gearing for Display I/Os
- Generic DDR, DDRX2, DDRX4
- Dedicated DDR/DDR2/LPDDR memory with DQS support

■ High Performance, Flexible I/O Buffer

- Programmable sysIO[™] buffer supports wide range of interfaces:
 - LVCMOS 3.3/2.5/1.8/1.5/1.2
 - LVTTL
 - PCI
 - LVDS, Bus-LVDS, MLVDS, RSDS, LVPECL
 - SSTL 25/18
 - HSTL 18
 - Schmitt trigger inputs, up to 0.5 V hysteresis
- I/Os support hot socketing
- On-chip differential termination
- · Programmable pull-up or pull-down mode

- Flexible On-Chip Clocking
 - · Eight primary clocks
 - Up to two edge clocks for high-speed I/O interfaces (top and bottom sides only)
 - Up to two analog PLLs per device with fractional-n frequency synthesis
 - Wide input frequency range (7 MHz to 400 MHz)

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- Non-volatile, Infinitely Reconfigurable
 - Instant-on powers up in microseconds
 - Single-chip, secure solution
 - Programmable through JTAG, SPI or I²C
 - Supports background programming of non-volatile memory
 - Optional dual boot with external SPI memory
- TransFR[™] Reconfiguration
 - In-field logic update while system operates

Enhanced System Level Support

- On-chip hardened functions: SPI, I²C, timer/ counter
- On-chip oscillator with 5.5% accuracy
- Unique TraceID for system tracking
- One Time Programmable (OTP) mode
- Single power supply with extended operating range
- IEEE Standard 1149.1 boundary scan
- IEEE 1532 compliant in-system programming
- Broad Range of Package Options
 - TQFP, WLCSP, ucBGA, csBGA, caBGA, ftBGA, fpBGA, QFN package options
 - Small footprint package options
 As small as 2.5 mm x 2.5 mm
 - · Density migration supported
 - · Advanced halogen-free packaging



MachXO2 Family Data Sheet Architecture

March 2016

Data Sheet DS1035

Architecture Overview

The MachXO2 family architecture contains an array of logic blocks surrounded by Programmable I/O (PIO). The larger logic density devices in this family have sysCLOCK[™] PLLs and blocks of sysMEM Embedded Block RAM (EBRs). Figure 2-1 and Figure 2-2 show the block diagrams of the various family members.





Note: MachXO2-256, and MachXO2-640/U are similar to MachXO2-1200. MachXO2-256 has a lower LUT count and no PLL or EBR blocks. MachXO2-640 has no PLL, a lower LUT count and two EBR blocks. MachXO2-640U has a lower LUT count, one PLL and seven EBR blocks.

Figure 2-2. Top View of the MachXO2-4000 Device



Note: MachXO2-1200U, MachXO2-2000/U and MachXO2-7000 are similar to MachXO2-4000. MachXO2-1200U and MachXO2-2000 have a lower LUT count, one PLL, and eight EBR blocks. MachXO2-2000U has a lower LUT count, two PLLs, and 10 EBR blocks. MachXO2-7000 has a higher LUT count, two PLLs, and 26 EBR blocks.

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The logic blocks, Programmable Functional Unit (PFU) and sysMEM EBR blocks, are arranged in a two-dimensional grid with rows and columns. Each row has either the logic blocks or the EBR blocks. The PIO cells are located at the periphery of the device, arranged in banks. The PFU contains the building blocks for logic, arithmetic, RAM, ROM, and register functions. The PIOs utilize a flexible I/O buffer referred to as a sysIO buffer that supports operation with a variety of interface standards. The blocks are connected with many vertical and horizontal routing channel resources. The place and route software tool automatically allocates these routing resources.

In the MachXO2 family, the number of sysIO banks varies by device. There are different types of I/O buffers on the different banks. Refer to the details in later sections of this document. The sysMEM EBRs are large, dedicated fast memory blocks; these blocks are found in MachXO2-640/U and larger devices. These blocks can be configured as RAM, ROM or FIFO. FIFO support includes dedicated FIFO pointer and flag "hard" control logic to minimize LUT usage.

The MachXO2 registers in PFU and sysl/O can be configured to be SET or RESET. After power up and device is configured, the device enters into user mode with these registers SET/RESET according to the configuration setting, allowing device entering to a known state for predictable system function.

The MachXO2 architecture also provides up to two sysCLOCK Phase Locked Loop (PLL) blocks on MachXO2-640U, MachXO2-1200/U and larger devices. These blocks are located at the ends of the on-chip Flash block. The PLLs have multiply, divide, and phase shifting capabilities that are used to manage the frequency and phase relationships of the clocks.

MachXO2 devices provide commonly used hardened functions such as SPI controller, I²C controller and timer/ counter. MachXO2-640/U and higher density devices also provide User Flash Memory (UFM). These hardened functions and the UFM interface to the core logic and routing through a WISHBONE interface. The UFM can also be accessed through the SPI, I²C and JTAG ports.

Every device in the family has a JTAG port that supports programming and configuration of the device as well as access to the user logic. The MachXO2 devices are available for operation from 3.3 V, 2.5 V and 1.2 V power supplies, providing easy integration into the overall system.

PFU Blocks

The core of the MachXO2 device consists of PFU blocks, which can be programmed to perform logic, arithmetic, distributed RAM and distributed ROM functions. Each PFU block consists of four interconnected slices numbered 0 to 3 as shown in Figure 2-3. Each slice contains two LUTs and two registers. There are 53 inputs and 25 outputs associated with each PFU block.



PIO

The PIO contains three blocks: an input register block, output register block and tri-state register block. These blocks contain registers for operating in a variety of modes along with the necessary clock and selection logic.

Table 2-8.	ΡΙΟ	Signal	List
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Pin Name	I/О Туре	Description
CE	Input	Clock Enable
D	Input	Pin input from sysIO buffer.
INDD	Output	Register bypassed input.
INCK	Output	Clock input
Q0	Output	DDR positive edge input
Q1	Output	Registered input/DDR negative edge input
D0	Input	Output signal from the core (SDR and DDR)
D1	Input	Output signal from the core (DDR)
TD	Input	Tri-state signal from the core
Q	Output	Data output signals to sysIO Buffer
TQ	Output	Tri-state output signals to sysIO Buffer
DQSR901	Input	DQS shift 90-degree read clock
DQSW90 ¹	Input	DQS shift 90-degree write clock
DDRCLKPOL ¹	Input	DDR input register polarity control signal from DQS
SCLK	Input	System clock for input and output/tri-state blocks.
RST	Input	Local set reset signal

1. Available in PIO on right edge only.

Input Register Block

The input register blocks for the PIOs on all edges contain delay elements and registers that can be used to condition high-speed interface signals before they are passed to the device core. In addition to this functionality, the input register blocks for the PIOs on the right edge include built-in logic to interface to DDR memory.

Figure 2-12 shows the input register block for the PIOs located on the left, top and bottom edges. Figure 2-13 shows the input register block for the PIOs on the right edge.

Left, Top, Bottom Edges

Input signals are fed from the sysIO buffer to the input register block (as signal D). If desired, the input signal can bypass the register and delay elements and be used directly as a combinatorial signal (INDD), and a clock (INCK). If an input delay is desired, users can select a fixed delay. I/Os on the bottom edge also have a dynamic delay, DEL[4:0]. The delay, if selected, reduces input register hold time requirements when using a global clock. The input block allows two modes of operation. In single data rate (SDR) the data is registered with the system clock (SCLK) by one of the registers in the single data rate sync register block. In Generic DDR mode, two registers are used to sample the data on the positive and negative edges of the system clock (SCLK) signal, creating two data streams.



Output Register Block

The output register block registers signals from the core of the device before they are passed to the sysIO buffers.

Left, Top, Bottom Edges

In SDR mode, D0 feeds one of the flip-flops that then feeds the output. The flip-flop can be configured as a D-type register or latch.

In DDR generic mode, D0 and D1 inputs are fed into registers on the positive edge of the clock. At the next falling edge the registered D1 input is registered into the register Q1. A multiplexer running off the same clock is used to switch the mux between the outputs of registers Q0 and Q1 that will then feed the output.

Figure 2-14 shows the output register block on the left, top and bottom edges.

Figure 2-14. MachXO2 Output Register Block Diagram (PIO on the Left, Top and Bottom Edges)



Right Edge

The output register block on the right edge is a superset of the output register on left, top and bottom edges of the device. In addition to supporting SDR and Generic DDR modes, the output register blocks for PIOs on the right edge include additional logic to support DDR-memory interfaces. Operation of this block is similar to that of the output register block on other edges.

In DDR memory mode, D0 and D1 inputs are fed into registers on the positive edge of the clock. At the next falling edge the registered D1 input is registered into the register Q1. A multiplexer running off the DQSW90 signal is used to switch the mux between the outputs of registers Q0 and Q1 that will then feed the output.

Figure 2-15 shows the output register block on the right edge.



More information on the input gearbox is available in TN1203, Implementing High-Speed Interfaces with MachXO2 Devices.

Output Gearbox

Each PIC on the top edge has a built-in 8:1 output gearbox. Each of these output gearboxes may be programmed as a 7:1 serializer or as one ODDRX4 (8:1) gearbox or as two ODDRX2 (4:1) gearboxes. Table 2-10 shows the gearbox signals.

Table 2-10. Output Gearbox Signal List

Name	I/O Type	Description
Q	Output	High-speed data output
D[7:0]	Input	Low-speed data from device core
Video TX(7:1): D[6:0]		
GDDRX4(8:1): D[7:0]		
GDDRX2(4:1)(IOL-A): D[3:0]		
GDDRX2(4:1)(IOL-C): D[7:4]		
SCLK	Input	Slow-speed system clock
ECLK [1:0]	Input	High-speed edge clock
RST	Input	Reset

The gearboxes have three stage pipeline registers. The first stage registers sample the low-speed input data on the low-speed system clock. The second stage registers transfer data from the low-speed clock registers to the high-speed clock registers. The third stage pipeline registers controlled by high-speed edge clock shift and mux the high-speed data out to the sysIO buffer. Figure 2-17 shows the output gearbox block diagram.



Figure 2-17. Output Gearbox



More information on the output gearbox is available in TN1203, Implementing High-Speed Interfaces with MachXO2 Devices.



Table 2-13. Supported Output Standards

Output Standard	V _{CCIO} (Typ.)
Single-Ended Interfaces	
LVTTL	3.3
LVCMOS33	3.3
LVCMOS25	2.5
LVCMOS18	1.8
LVCMOS15	1.5
LVCMOS12	1.2
LVCMOS33, Open Drain	—
LVCMOS25, Open Drain	—
LVCMOS18, Open Drain	—
LVCMOS15, Open Drain	—
LVCMOS12, Open Drain	—
PCI33	3.3
SSTL25 (Class I)	2.5
SSTL18 (Class I)	1.8
HSTL18(Class I)	1.8
Differential Interfaces	
LVDS ^{1, 2}	2.5, 3.3
BLVDS, MLVDS, RSDS ²	2.5
LVPECL ²	3.3
MIPI ²	2.5
Differential SSTL18	1.8
Differential SSTL25	2.5
Differential HSTL18	1.8

1. MachXO2-640U, MachXO2-1200/U and larger devices have dedicated LVDS buffers. 2. These interfaces can be emulated with external resistors in all devices.

sysIO Buffer Banks

The numbers of banks vary between the devices of this family. MachXO2-1200U, MachXO2-2000/U and higher density devices have six I/O banks (one bank on the top, right and bottom side and three banks on the left side). The MachXO2-1200 and lower density devices have four banks (one bank per side). Figures 2-18 and 2-19 show the sysIO banks and their associated supplies for all devices.



There are some limitations on the use of the hardened user SPI. These are defined in the following technical notes:

- TN1087, Minimizing System Interruption During Configuration Using TransFR Technology (Appendix B)
- TN1205, Using User Flash Memory and Hardened Control Functions in MachXO2 Devices

Figure 2-22. SPI Core Block Diagram



Table 2-16 describes the signals interfacing with the SPI cores.

Table 2-16. SPI Core Signal Description

Signal Name	I/O	Master/Slave	Description
spi_csn[0]	0	Master	SPI master chip-select output
spi_csn[17]	0	Master	Additional SPI chip-select outputs (total up to eight slaves)
spi_scsn	I	Slave	SPI slave chip-select input
spi_irq	0	Master/Slave	Interrupt request
spi_clk	I/O	Master/Slave	SPI clock. Output in master mode. Input in slave mode.
spi_miso	I/O	Master/Slave	SPI data. Input in master mode. Output in slave mode.
spi_mosi	I/O	Master/Slave	SPI data. Output in master mode. Input in slave mode.
ufm_sn	I	Slave	Configuration Slave Chip Select (active low), dedicated for selecting the User Flash Memory (UFM).
cfg_stdby	0	Master/Slave	Stand-by signal – To be connected only to the power module of the MachXO2 device. The signal is enabled only if the "Wakeup Enable" feature has been set within the EFB GUI, SPI Tab.
cfg_wake	0	Master/Slave	Wake-up signal – To be connected only to the power module of the MachXO2 device. The signal is enabled only if the "Wakeup Enable" feature has been set within the EFB GUI, SPI Tab.



MachXO2 Family Data Sheet DC and Switching Characteristics

March 2017

Data Sheet DS1035

Absolute Maximum Ratings^{1, 2, 3}

	MachXO2 ZE/HE (1.2 V)	MachXO2 HC (2.5 V / 3.3 V)
Supply Voltage V _{CC}	–0.5 V to 1.32 V	0.5 V to 3.75 V
Output Supply Voltage V _{CCIO}	–0.5 V to 3.75 V	0.5 V to 3.75 V
I/O Tri-state Voltage Applied ^{4, 5}	–0.5 V to 3.75 V	0.5 V to 3.75 V
Dedicated Input Voltage Applied ⁴	–0.5 V to 3.75 V	0.5 V to 3.75 V
Storage Temperature (Ambient)	–55 °C to 125 °C	–55 °C to 125 °C
Junction Temperature (T_1)	–40 °C to 125 °C	–40 °C to 125 °C

1. Stress above those listed under the "Absolute Maximum Ratings" may cause permanent damage to the device. Functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

2. Compliance with the Lattice Thermal Management document is required.

3. All voltages referenced to GND.

4. Overshoot and undershoot of -2 V to (V_{IHMAX} + 2) volts is permitted for a duration of <20 ns.

5. The dual function I^2C pins SCL and SDA are limited to -0.25 V to 3.75 V or to -0.3 V with a duration of <20 ns.

Recommended Operating Conditions¹

Symbol	Parameter	Min.	Max.	Units
V _{CC} ¹	Core Supply Voltage for 1.2 V Devices	1.14	1.26	V
	Core Supply Voltage for 2.5 V / 3.3 V Devices	2.375	3.6	V
V _{CCIO} ^{1, 2, 3}	I/O Driver Supply Voltage	1.14	3.6	V
t _{JCOM}	Junction Temperature Commercial Operation	0	85	°C
t _{JIND}	Junction Temperature Industrial Operation	-40	100	°C

1. Like power supplies must be tied together. For example, if V_{CCIO} and V_{CC} are both the same voltage, they must also be the same supply.

2. See recommended voltages by I/O standard in subsequent table.

3. V_{CCIO} pins of unused I/O banks should be connected to the V_{CC} power supply on boards.

Power Supply Ramp Rates¹

Symbol	Parameter	Min.	Тур.	Max.	Units
t _{RAMP}	Power supply ramp rates for all power supplies.	0.01		100	V/ms

1. Assumes monotonic ramp rates.

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			-6		-5		-4		
Parameter	Description	Device	Min.	Max.	Min.	Max.	Min.	Max.	Units
		MachXO2-1200HC-HE	0.41		0.48		0.55	—	ns
1	Clock to Data Hold – PIO Input	MachXO2-2000HC-HE	0.42		0.49		0.56	—	ns
THPLL	Register	MachXO2-4000HC-HE	0.43		0.50		0.58	—	ns
		MachXO2-7000HC-HE	0.46		0.54		0.62	—	ns
		MachXO2-1200HC-HE	2.88		3.19		3.72	—	ns
	Clock to Data Setup – PIO	MachXO2-2000HC-HE	2.87		3.18		3.70	—	ns
^I SU_DELPLL	Delav	MachXO2-4000HC-HE	2.96		3.28		3.81	—	ns
	5	MachXO2-7000HC-HE	3.05		3.35	—	3.87	—	ns
		MachXO2-1200HC-HE	-0.83		-0.83		-0.83	—	ns
t _{H_DELPLL}	Clock to Data Hold – PIO Input	MachXO2-2000HC-HE	-0.83		-0.83		-0.83	—	ns
	Register with Input Data Delay	MachXO2-4000HC-HE	-0.87		-0.87	—	-0.87	—	ns
		MachXO2-7000HC-HE	-0.91	—	-0.91	—	-0.91	—	ns
Generic DDF	RX1 Inputs with Clock and Data	Aligned at Pin Using PC	LK Pin	for Cloc	k Input -	GDDR	(1_RX.S	CLK.Ali	gned ^{9, 12}
t _{DVA}	Input Data Valid After CLK			0.317	—	0.344	—	0.368	UI
t _{DVE}	Input Data Hold After CLK	All MachXO2 devices, all sides	0.742	—	0.702	—	0.668	—	UI
f _{DATA}	DDRX1 Input Data Speed		_	300	—	250	—	208	Mbps
f _{DDRX1}	DDRX1 SCLK Frequency			150	—	125	—	104	MHz
Generic DDF	X1 Inputs with Clock and Data C	Centered at Pin Using PC	LK Pin f	or Clock	Input –	GDDRX	1_RX.SC	LK.Cen	tered ^{9, 12}
t _{SU}	Input Data Setup Before CLK		0.566		0.560		0.538	—	ns
t _{HO}	Input Data Hold After CLK	All MachXO2 devices,	0.778		0.879		1.090	—	ns
f _{DATA}	DDRX1 Input Data Speed	all sides		300		250		208	Mbps
f _{DDRX1}	DDRX1 SCLK Frequency			150		125		104	MHz
Generic DDF	RX2 Inputs with Clock and Data	Aligned at Pin Using PC	LK Pin f	for Clock	k Input –	GDDR	(2_RX.E	CLK.Ali	gned ^{9, 12}
t _{DVA}	Input Data Valid After CLK		—	0.316		0.342		0.364	UI
t _{DVE}	Input Data Hold After CLK	MachXO2-640U,	0.710		0.675		0.679	—	UI
f _{DATA}	DDRX2 Serial Input Data Speed	MachXO2-1200/U and larger devices,	_	664	_	554	_	462	Mbps
f _{DDRX2}	DDRX2 ECLK Frequency	bottom side only ¹¹		332		277		231	MHz
f _{SCLK}	SCLK Frequency			166		139	—	116	MHz
Generic DDF	X2 Inputs with Clock and Data C	Centered at Pin Using PC	LK Pin f	or Clock	Input –	GDDRX	2_RX.EC	LK.Cen	tered ^{9, 12}
t _{SU}	Input Data Setup Before CLK		0.233		0.219		0.198	—	ns
t _{HO}	Input Data Hold After CLK	MachXO2-640U	0.287	—	0.287	—	0.344	—	ns
f _{DATA}	DDRX2 Serial Input Data Speed	MachXO2-1200/U and larger devices,	_	664	_	554	_	462	Mbps
f _{DDRX2}	DDRX2 ECLK Frequency	bottom side only ¹¹	—	332	—	277	—	231	MHz
f _{SCLK}	SCLK Frequency	1	—	166		139		116	MHz



	-6		-	-5		-4			
Parameter	Description	Device	Min.	Max.	Min.	Max.	Min.	Max.	Units
Generic DDF	R4 Inputs with Clock and Data	ligned at Pin Using PC	LK Pin f	or Clock	Input –	GDDRX	4_RX.E	CLK.Ali	gned ^{9, 12}
t _{DVA}	Input Data Valid After ECLK		_	0.290	_	0.320	—	0.345	UI
t _{DVE}	Input Data Hold After ECLK	MachXO2-640U.	0.739	—	0.699	—	0.703	—	UI
f _{DATA}	DDRX4 Serial Input Data Speed	MachXO2-1200/U and larger devices,	_	756		630	—	524	Mbps
f _{DDRX4}	DDRX4 ECLK Frequency	bottom side only.11	—	378	_	315	—	262	MHz
f _{SCLK}	SCLK Frequency			95	_	79	—	66	MHz
Generic DDF	R4 Inputs with Clock and Data C	entered at Pin Using PCI	LK Pin f	or Clock	Input –	GDDRX4	4_RX.EC	LK.Cen	tered ^{9, 12}
t _{SU}	Input Data Setup Before ECLK		0.233	—	0.219	—	0.198		ns
t _{HO}	Input Data Hold After ECLK	MachXO2-640U,	0.287	—	0.287	—	0.344	_	ns
f _{DATA}	DDRX4 Serial Input Data Speed	MachXO2-1200/U and larger devices,	_	756		630	—	524	Mbps
f _{DDRX4}	DDRX4 ECLK Frequency	bottom side only.11	_	378	_	315	—	262	MHz
f _{SCLK}	SCLK Frequency			95	_	79	—	66	MHz
7:1 LVDS In	puts (GDDR71_RX.ECLK.7:1) ^{9,}	12		•		•	1		
t _{DVA}	Input Data Valid After ECLK	MachXO2-640U, MachXO2-1200/U and larger devices, bottom side only. ¹¹		0.290		0.320	—	0.345	UI
t _{DVE}	Input Data Hold After ECLK		0.739	—	0.699	—	0.703		UI
f _{DATA}	DDR71 Serial Input Data Speed			756		630		524	Mbps
f _{DDR71}	DDR71 ECLK Frequency			378		315	—	262	MHz
f _{CLKIN}	7:1 Input Clock Frequency (SCLK) (minimum limited by PLL)		_	108	_	90	_	75	MHz
Generic DDF	R Outputs with Clock and Data	Aligned at Pin Using PC	LK Pin f	for Clock	c Input –	GDDR	(1_TX.S	CLK.Ali	gned ^{9, 12}
t _{DIA}	Output Data Invalid After CLK Output		_	0.520	_	0.550	_	0.580	ns
t _{DIB}	Output Data Invalid Before CLK Output	All MachXO2 devices, all sides.	_	0.520	_	0.550	_	0.580	ns
f _{DATA}	DDRX1 Output Data Speed		_	300	_	250		208	Mbps
f _{DDBX1}	DDRX1 SCLK frequency			150	_	125		104	MHz
Generic DDF	Outputs with Clock and Data C	entered at Pin Using PC	LK Pin f	or Clock	Input –	GDDRX	1_TX.SC	LK.Cen	tered ^{9, 12}
t _{DVB}	Output Data Valid Before CLK Output		1.210	_	1.510	_	1.870	_	ns
t _{DVA}	Output Data Valid After CLK Output	All MachXO2 devices,	1.210	_	1.510	_	1.870	_	ns
f _{DATA}	DDRX1 Output Data Speed	all sides.	_	300	_	250	_	208	Mbps
f _{DDRX1}	DDRX1 SCLK Frequency (minimum limited by PLL)		_	150	_	125	_	104	MHz
Generic DDF	X2 Outputs with Clock and Data	Aligned at Pin Using P	CLK Pin	for Cloc	k Input	GDDR	X2_TX.E	CLK.Ali	gned ^{9, 12}
t _{DIA}	Output Data Invalid After CLK Output		_	0.200	_	0.215	_	0.230	ns
t _{DIB}	Output Data Invalid Before CLK Output	MachXO2-640U, MachXO2-1200/LL and		0.200		0.215		0.230	ns
f _{DATA}	DDRX2 Serial Output Data Speed	larger devices, top side only.	_	664	_	554	_	462	Mbps
f _{DDRX2}	DDRX2 ECLK frequency	1	—	332	_	277	—	231	MHz
f _{SCLK}	SCLK Frequency	1	—	166	—	139	—	116	MHz



			-6		-5		-4		
Parameter	Description	Device	Min.	Max.	Min.	Max.	Min.	Max.	Units
LPDDR ^{9, 12}	·	·			•	•			
t _{DVADQ}	Input Data Valid After DQS Input		_	0.369	_	0.395	_	0.421	UI
t _{DVEDQ}	Input Data Hold After DQS Input		0.529	_	0.530	_	0.527	_	UI
t _{DQVBS}	Output Data Invalid Before DQS Output	MachXO2-1200/U and	0.25	_	0.25		0.25	_	UI
t _{DQVAS}	Output Data Invalid After DQS Output	larger devices, right side only. ¹³	0.25	_	0.25	_	0.25	_	UI
f _{DATA}	MEM LPDDR Serial Data Speed		_	280	_	250	_	208	Mbps
f _{SCLK}	SCLK Frequency			140	—	125	—	104	MHz
f _{LPDDR}	LPDDR Data Transfer Rate		0	280	0	250	0	208	Mbps
DDR ^{9, 12}									
t _{DVADQ}	Input Data Valid After DQS Input	-	_	0.350	_	0.387	_	0.414	UI
t _{DVEDQ}	Input Data Hold After DQS Input		0.545	_	0.538		0.532	_	UI
t _{DQVBS}	Output Data Invalid Before DQS Output	MachXO2-1200/U and larger devices, right	0.25	_	0.25	_	0.25	_	UI
t _{DQVAS}	Output Data Invalid After DQS Output	side only. ¹³	0.25	_	0.25	_	0.25	_	UI
f _{DATA}	MEM DDR Serial Data Speed			300	—	250	—	208	Mbps
f _{SCLK}	SCLK Frequency			150	—	125	—	104	MHz
f _{MEM_DDR}	MEM DDR Data Transfer Rate		N/A	300	N/A	250	N/A	208	Mbps
DDR2 ^{9, 12}									
t _{DVADQ}	Input Data Valid After DQS Input		_	0.360	_	0.378	_	0.406	UI
t _{DVEDQ}	Input Data Hold After DQS Input		0.555	_	0.549	_	0.542	_	UI
t _{DQVBS}	Output Data Invalid Before DQS Output	MachXO2-1200/U and	0.25	_	0.25	_	0.25	_	UI
t _{DQVAS}	Output Data Invalid After DQS Output	larger devices, right side only. ¹³	0.25	_	0.25	_	0.25	_	UI
f _{DATA}	MEM DDR Serial Data Speed	1	—	300	—	250	—	208	Mbps
f _{SCLK}	SCLK Frequency	1	—	150	—	125	—	104	MHz
f _{MEM_DDR2}	MEM DDR2 Data Transfer Rate		N/A	300	N/A	250	N/A	208	Mbps

1. Exact performance may vary with device and design implementation. Commercial timing numbers are shown at 85 °C and 1.14 V. Other operating conditions, including industrial, can be extracted from the Diamond software.

2. General I/O timing numbers based on LVCMOS 2.5, 8 mA, 0pf load, fast slew rate.

3. Generic DDR timing numbers based on LVDS I/O (for input, output, and clock ports).

4. DDR timing numbers based on SSTL25. DDR2 timing numbers based on SSTL18. LPDDR timing numbers based in LVCMOS18.

5. 7:1 LVDS (GDDR71) uses the LVDS I/O standard (for input, output, and clock ports).

6. For Generic DDRX1 mode $t_{SU} = t_{HO} = (t_{DVE} - t_{DVA} - 0.03 \text{ ns})/2$.

7. The $t_{SU_{DEL}}$ and $t_{H_{DEL}}$ values use the SCLK_ZERHOLD default step size. Each step is 105 ps (-6), 113 ps (-5), 120 ps (-4).

8. This number for general purpose usage. Duty cycle tolerance is +/- 10%.

9. Duty cycle is +/-5% for system usage.

10. The above timing numbers are generated using the Diamond design tool. Exact performance may vary with the device selected.

11. High-speed DDR and LVDS not supported in SG32 (32 QFN) packages.

12. Advance information for MachXO2 devices in 48 QFN packages.

13. DDR memory interface not supported in QN84 (84 QFN) and SG32 (32 QFN) packages.



			-3		-3 -2		-1		
Parameter	Description	Device	Min.	Max.	Min.	Max.	Min.	Max.	Units
Generic DDR	(2 Outputs with Clock and Data C	Centered at Pin Using P	CLK Pin	for Cloc	k Input –	GDDRX	2_TX.EC	CLK.Cen	tered ^{9, 12}
t _{DVB}	Output Data Valid Before CLK Output		1.445	_	1.760	_	2.140	_	ns
t _{DVA}	Output Data Valid After CLK Output	MachXO2-640U, MachXO2-1200/U and larger devices, top side only	1.445	_	1.760	_	2.140	_	ns
f _{DATA}	DDRX2 Serial Output Data Speed		_	280	_	234	_	194	Mbps
f _{DDRX2}	DDRX2 ECLK Frequency (minimum limited by PLL)		_	140	_	117	_	97	MHz
f _{SCLK}	SCLK Frequency		—	70	—	59	_	49	MHz
Generic DDR	X4 Outputs with Clock and Data	Aligned at Pin Using P	CLK Pin	for Cloc	k Input	- GDDR	X4_TX.E	CLK.Ali	gned ^{9, 12}
t _{DIA}	Output Data Invalid After CLK Output		_	0.270	_	0.300	_	0.330	ns
t _{DIB}	Output Data Invalid Before CLK Output	MachXO2-640U, MachXO2-1200/U and larger devices, top side only	_	0.270	_	0.300	_	0.330	ns
f _{DATA}	DDRX4 Serial Output Data Speed		_	420	_	352	_	292	Mbps
f _{DDRX4}	DDRX4 ECLK Frequency		_	210	—	176	—	146	MHz
f _{SCLK}	SCLK Frequency		_	53		44		37	MHz
Generic DDR	(4 Outputs with Clock and Data (Centered at Pin Using P	CLK Pin	for Cloc	k Input –	GDDRX	4_TX.EC	CLK.Cen	tered ^{9, 12}
t _{DVB}	Output Data Valid Before CLK Output		0.873	_	1.067	_	1.319	_	ns
t _{DVA}	Output Data Valid After CLK Output	MachXO2-640U,	0.873	_	1.067	_	1.319	_	ns
f _{DATA}	DDRX4 Serial Output Data Speed	and larger devices,	_	420	_	352	_	292	Mbps
f _{DDRX4}	DDRX4 ECLK Frequency (minimum limited by PLL)		_	210	_	176	_	146	MHz
f _{SCLK}	SCLK Frequency		—	53	—	44	_	37	MHz
7:1 LVDS Ou	tputs – GDDR71_TX.ECLK.7:1	9, 12							
t _{DIB}	Output Data Invalid Before CLK Output		_	0.240	—	0.270	_	0.300	ns
t _{DIA}	Output Data Invalid After CLK Output	MachXO2-640U	_	0.240	_	0.270	_	0.300	ns
f _{DATA}	DDR71 Serial Output Data Speed	MachXO2-1200/U and larger devices,	_	420	_	352	_	292	Mbps
f _{DDR71}	DDR71 ECLK Frequency	top side only.	—	210	—	176	—	146	MHz
fclkout	7:1 Output Clock Frequency (SCLK) (minimum limited by PLL)		_	60	_	50	_	42	MHz



sysCLOCK PLL Timing (Continued)

Over Recommended Operating Conditions

Parameter	Descriptions	Conditions	Min.	Max.	Units
t _{ROTATE_WD}	PHASESTEP Pulse Width		4		VCO Cycles

1. Period jitter sample is taken over 10,000 samples of the primary PLL output with a clean reference clock. Cycle-to-cycle jitter is taken over 1000 cycles. Phase jitter is taken over 2000 cycles. All values per JESD65B.

2. Output clock is valid after t_{LOCK} for PLL reset and dynamic delay adjustment.

3. Using LVDS output buffers.

4. CLKOS as compared to CLKOP output for one phase step at the maximum VCO frequency. See TN1199, MachXO2 sysCLOCK PLL Design and Usage Guide for more details.

5. At minimum f_{PFD} As the f_{PFD} increases the time will decrease to approximately 60% the value listed.

6. Maximum allowed jitter on an input clock. PLL unlock may occur if the input jitter exceeds this specification. Jitter on the input clock may be transferred to the output clocks, resulting in jitter measurements outside the output specifications listed in this table.

7. Edge Duty Trim Accuracy is a percentage of the setting value. Settings available are 70 ps, 140 ps, and 280 ps in addition to the default value of none.

8. Jitter values measured with the internal oscillator operating. The jitter values will increase with loading of the PLD fabric and in the presence of SSO noise.



				MachX	02-4000			
	84 QFN	132 csBGA	144 TQFP	184 csBGA	256 caBGA	256 ftBGA	332 caBGA	484 fpBGA
General Purpose I/O per Bank								
Bank 0	27	25	27	37	50	50	68	70
Bank 1	10	26	29	37	52	52	68	68
Bank 2	22	28	29	39	52	52	70	72
Bank 3	0	7	9	10	16	16	24	24
Bank 4	9	8	10	12	16	16	16	16
Bank 5	0	10	10	15	20	20	28	28
Total General Purpose Single Ended I/O	68	104	114	150	206	206	274	278
Differential I/O per Bank								
Bank 0	13	13	14	18	25	25	34	35
Bank 1	4	13	14	18	26	26	34	34
Bank 2	11	14	14	19	26	26	35	36
Bank 3	0	3	4	4	8	8	12	12
Bank 4	4	4	5	6	8	8	8	8
Bank 5	0	5	5	7	10	10	14	14
Total General Purpose Differential I/O	32	52	56	72	103	103	137	139
Dual Function I/O	28	37	37	37	37	37	37	37
High-speed Differential I/O								
Bank 0	8	8	9	8	18	18	18	18
Gearboxes					-			-
Number of 7:1 or 8:1 Output Gearbox Available (Bank 0)	8	8	9	9	18	18	18	18
Number of 7:1 or 8:1 Input Gearbox Available (Bank 2)	11	14	14	12	18	18	18	18
DQS Groups								
Bank 1	1	2	2	2	2	2	2	2
VCCIO Pins								
Bank 0	3	3	3	3	4	4	4	10
Bank 1	1	3	3	3	4	4	4	10
Bank 2	2	3	3	3	4	4	4	10
Bank 3	1	1	1	1	1	1	2	3
Bank 4	1	1	1	1	2	2	1	4
Bank 5	1	1	1	1	1	1	2	3
		1						
VCC	4	4	4	4	8	8	8	12
GND	4	10	12	16	24	24	27	48
NC	1	1	1	1	1	1	5	105
Reserved for configuration	1	1	1	1	1	1	1	1
Total Count of Bonded Pins	84	132	144	184	256	256	332	484



Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-7000HC-4TG144C	6864	2.5 V / 3.3 V	-4	Halogen-Free TQFP	144	СОМ
LCMXO2-7000HC-5TG144C	6864	2.5 V / 3.3 V	-5	Halogen-Free TQFP	144	COM
LCMXO2-7000HC-6TG144C	6864	2.5 V / 3.3 V	-6	Halogen-Free TQFP	144	COM
LCMXO2-7000HC-4BG256C	6864	2.5 V / 3.3 V	-4	Halogen-Free caBGA	256	COM
LCMXO2-7000HC-5BG256C	6864	2.5 V / 3.3 V	-5	Halogen-Free caBGA	256	COM
LCMXO2-7000HC-6BG256C	6864	2.5 V / 3.3 V	-6	Halogen-Free caBGA	256	COM
LCMXO2-7000HC-4FTG256C	6864	2.5 V / 3.3 V	-4	Halogen-Free ftBGA	256	COM
LCMXO2-7000HC-5FTG256C	6864	2.5 V / 3.3 V	-5	Halogen-Free ftBGA	256	COM
LCMXO2-7000HC-6FTG256C	6864	2.5 V / 3.3 V	-6	Halogen-Free ftBGA	256	COM
LCMXO2-7000HC-4BG332C	6864	2.5 V / 3.3 V	-4	Halogen-Free caBGA	332	COM
LCMXO2-7000HC-5BG332C	6864	2.5 V / 3.3 V	-5	Halogen-Free caBGA	332	COM
LCMXO2-7000HC-6BG332C	6864	2.5 V / 3.3 V	-6	Halogen-Free caBGA	332	COM
LCMXO2-7000HC-4FG400C	6864	2.5 V / 3.3 V	-4	Halogen-Free fpBGA	400	COM
LCMXO2-7000HC-5FG400C	6864	2.5 V / 3.3 V	-5	Halogen-Free fpBGA	400	COM
LCMXO2-7000HC-6FG400C	6864	2.5 V / 3.3 V	-6	Halogen-Free fpBGA	400	COM
LCMXO2-7000HC-4FG484C	6864	2.5 V / 3.3 V	-4	Halogen-Free fpBGA	484	COM
LCMXO2-7000HC-5FG484C	6864	2.5 V / 3.3 V	-5	Halogen-Free fpBGA	484	COM
LCMXO2-7000HC-6FG484C	6864	2.5 V / 3.3 V	-6	Halogen-Free fpBGA	484	COM

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-1200HC-4TG100CR1 ¹	1280	2.5 V / 3.3 V	-4	Halogen-Free TQFP	100	COM
LCMXO2-1200HC-5TG100CR1 ¹	1280	2.5 V / 3.3 V	-5	Halogen-Free TQFP	100	COM
LCMXO2-1200HC-6TG100CR1 ¹	1280	2.5 V / 3.3 V	-6	Halogen-Free TQFP	100	COM
LCMXO2-1200HC-4MG132CR11	1280	2.5 V / 3.3 V	-4	Halogen-Free csBGA	132	COM
LCMXO2-1200HC-5MG132CR11	1280	2.5 V / 3.3 V	-5	Halogen-Free csBGA	132	COM
LCMXO2-1200HC-6MG132CR11	1280	2.5 V / 3.3 V	-6	Halogen-Free csBGA	132	COM
LCMXO2-1200HC-4TG144CR1 ¹	1280	2.5 V / 3.3 V	-4	Halogen-Free TQFP	144	COM
LCMXO2-1200HC-5TG144CR1 ¹	1280	2.5 V / 3.3 V	-5	Halogen-Free TQFP	144	COM
LCMXO2-1200HC-6TG144CR11	1280	2.5 V / 3.3 V	-6	Halogen-Free TQFP	144	COM

1. Specifications for the "LCMXO2-1200HC-speed package CR1" are the same as the "LCMXO2-1200HC-speed package C" devices respectively, except as specified in the R1 Device Specifications section of this data sheet.



Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-1200ZE-1TG100IR11	1280	1.2 V	-1	Halogen-Free TQFP	100	IND
LCMXO2-1200ZE-2TG100IR11	1280	1.2 V	-2	Halogen-Free TQFP	100	IND
LCMXO2-1200ZE-3TG100IR11	1280	1.2 V	-3	Halogen-Free TQFP	100	IND
LCMXO2-1200ZE-1MG132IR1 ¹	1280	1.2 V	-1	Halogen-Free csBGA	132	IND
LCMXO2-1200ZE-2MG132IR1 ¹	1280	1.2 V	-2	Halogen-Free csBGA	132	IND
LCMXO2-1200ZE-3MG132IR11	1280	1.2 V	-3	Halogen-Free csBGA	132	IND
LCMXO2-1200ZE-1TG144IR11	1280	1.2 V	-1	Halogen-Free TQFP	144	IND
LCMXO2-1200ZE-2TG144IR11	1280	1.2 V	-2	Halogen-Free TQFP	144	IND
LCMXO2-1200ZE-3TG144IR11	1280	1.2 V	-3	Halogen-Free TQFP	144	IND

1. Specifications for the "LCMXO2-1200ZE-speed package IR1" are the same as the "LCMXO2-1200ZE-speed package I" devices respectively, except as specified in the R1 Device Specifications section of this data sheet.



Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-1200HC-4TG100IR11	1280	2.5 V / 3.3 V	-4	Halogen-Free TQFP	100	IND
LCMXO2-1200HC-5TG100IR11	1280	2.5 V / 3.3 V	-5	Halogen-Free TQFP	100	IND
LCMXO2-1200HC-6TG100IR11	1280	2.5 V / 3.3 V	-6	Halogen-Free TQFP	100	IND
LCMXO2-1200HC-4MG132IR11	1280	2.5 V / 3.3 V	-4	Halogen-Free csBGA	132	IND
LCMXO2-1200HC-5MG132IR1 ¹	1280	2.5 V / 3.3 V	-5	Halogen-Free csBGA	132	IND
LCMXO2-1200HC-6MG132IR11	1280	2.5 V / 3.3 V	-6	Halogen-Free csBGA	132	IND
LCMXO2-1200HC-4TG144IR1 ¹	1280	2.5 V / 3.3 V	-4	Halogen-Free TQFP	144	IND
LCMXO2-1200HC-5TG144IR1 ¹	1280	2.5 V / 3.3 V	-5	Halogen-Free TQFP	144	IND
LCMXO2-1200HC-6TG144IR11	1280	2.5 V / 3.3 V	-6	Halogen-Free TQFP	144	IND

1. Specifications for the "LCMXO2-1200HC-speed package IR1" are the same as the "LCMXO2-1200ZE-speed package I" devices respectively, except as specified in the R1 Device Specifications section of this data sheet.



R1 Device Specifications

The LCMXO2-1200ZE/HC "R1" devices have the same specifications as their Standard (non-R1) counterparts except as listed below. For more details on the R1 to Standard migration refer to AN8086, Designing for Migration from MachXO2-1200-R1 to Standard Non-R1) Devices.

- The User Flash Memory (UFM) cannot be programmed through the internal WISHBONE interface. It can still be programmed through the JTAG/SPI/I²C ports.
- The on-chip differential input termination resistor value is higher than intended. It is approximately 200Ω as opposed to the intended 100Ω. It is recommended to use external termination resistors for differential inputs. The on-chip termination resistors can be disabled through Lattice design software.
- Soft Error Detection logic may not produce the correct result when it is run for the first time after configuration. To use this feature, discard the result from the first operation. Subsequent operations will produce the correct result.
- Under certain conditions, IIH exceeds data sheet specifications. The following table provides more details:

Condition	Clamp	Pad Rising IIH Max.	Pad Falling IIH Min.	Steady State Pad High IIH	Steady State Pad Low IIL
VPAD > VCCIO	OFF	1 mA	–1 mA	1 mA	10 µA
VPAD = VCCIO	ON	10 µA	–10 μA	10 µA	10 µA
VPAD = VCCIO	OFF	1 mA	–1 mA	1 mA	10 µA
VPAD < VCCIO	OFF	10 µA	–10 μA	10 µA	10 µA

- The user SPI interface does not operate correctly in some situations. During master read access and slave write access, the last byte received does not generate the RRDY interrupt.
- In GDDRX2, GDDRX4 and GDDR71 modes, ECLKSYNC may have a glitch in the output under certain conditions, leading to possible loss of synchronization.
- When using the hard I²C IP core, the I²C status registers I2C_1_SR and I2C_2_SR may not update correctly.
- PLL Lock signal will glitch high when coming out of standby. This glitch lasts for about 10 μsec before returning low.
- Dual boot only available on HC devices, requires tying VCC and VCCIO2 to the same 3.3 V or 2.5 V supply.